

D1FM3**30V 5A****特長**

- 小型SMD
- 低 $V_F=0.46V$
- 低 $I_R=0.1mA$

Feature

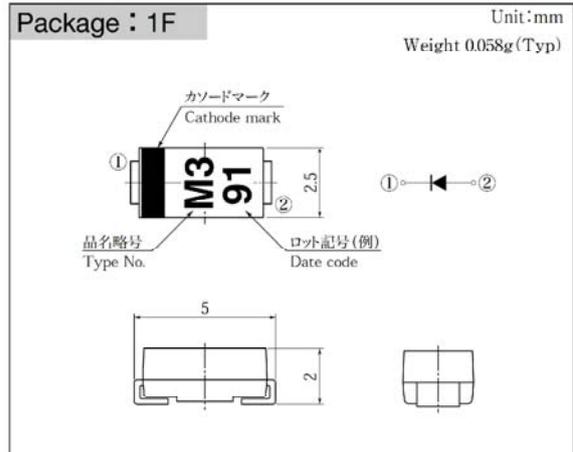
- Small SMD
- Low $V_F=0.46V$
- Low $I_R=0.1mA$

用途

- バッテリー逆接防止
- DC/DCコンバータ
- 携帯電話、パソコン

Main Use

- Reverse connect protection for DC power source
- DC/DC Converter
- Mobile phone, PC

■外観図 OUTLINE

外形図については新電元Webサイト又は〈半導体製品一覧表〉をご参照下さい。捺印表示については捺印仕様をご確認下さい。

For details of the outline dimensions, refer to our web site or Semiconductor Short Form Catalog. As for the marking, refer to the specification "Marking, Terminal Connection".

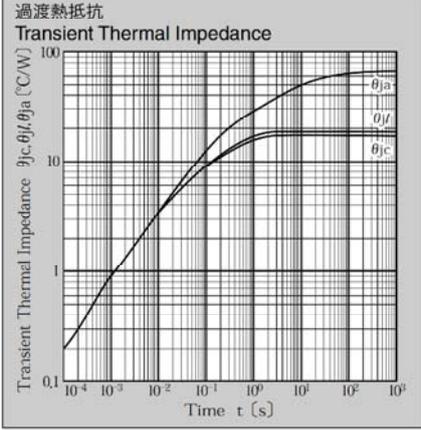
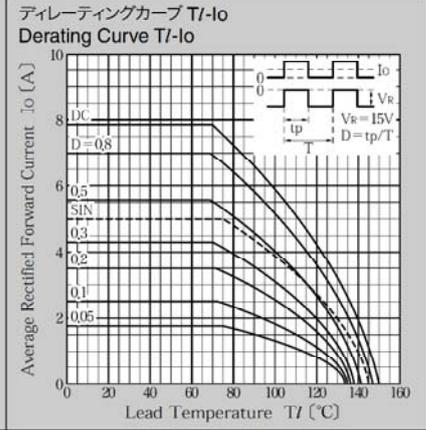
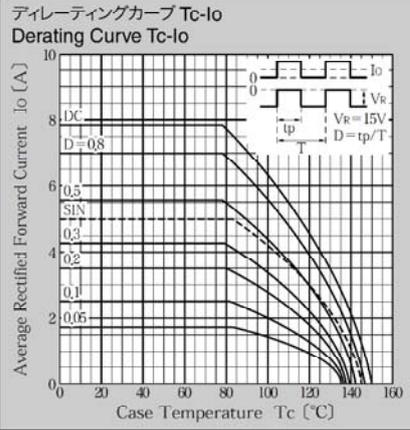
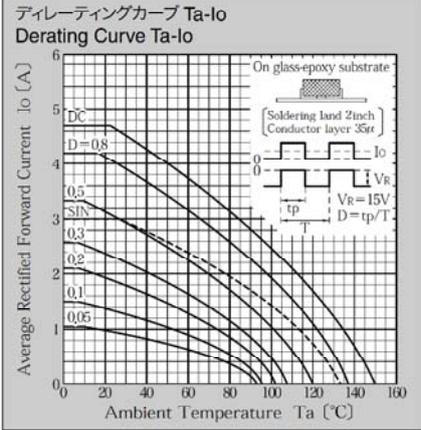
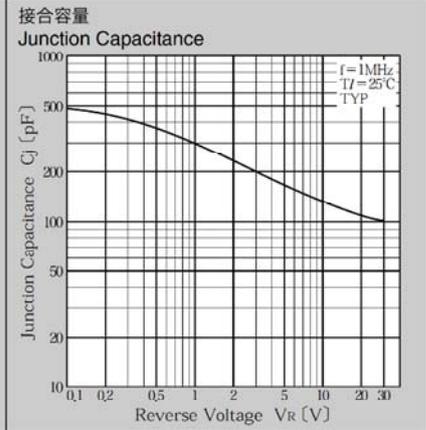
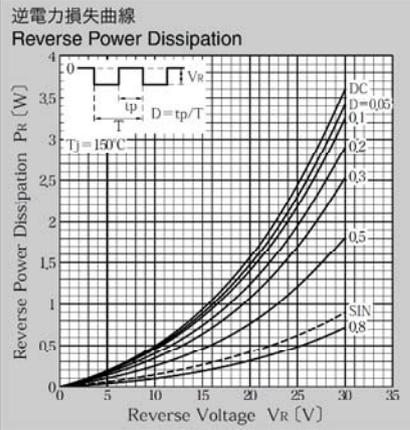
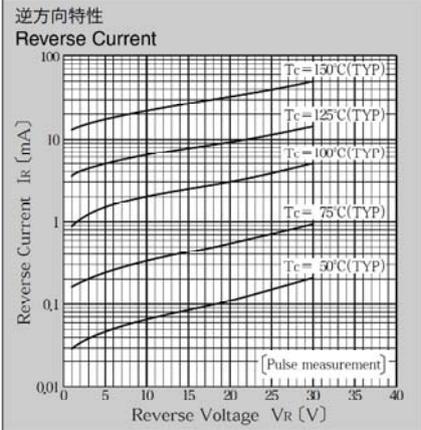
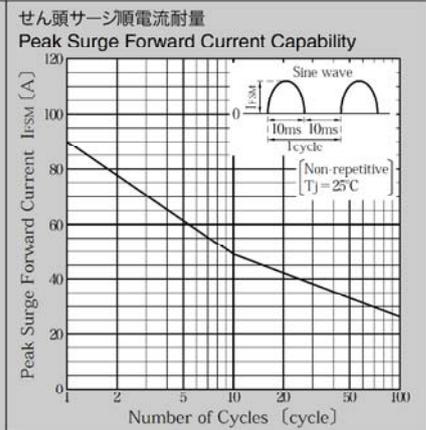
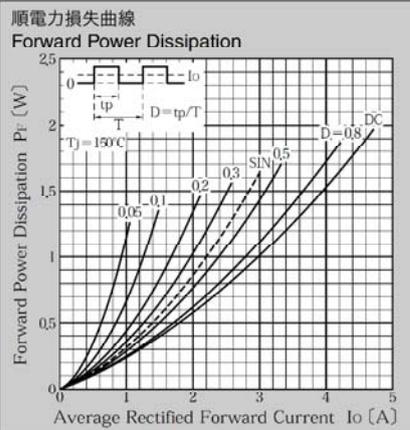
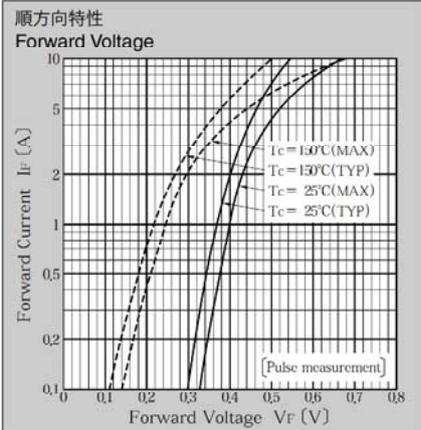
■定格表 RATINGS**●絶対最大定格 Absolute Maximum Ratings (指定のない場合 $T_C = 25^\circ C$)**

項目 Item	記号 Symbol	条件 Conditions	品名 Type No.	D1FM3	単位 Unit
保存温度 Storage Temperature	T_{stg}			-55~150	$^\circ C$
接合部温度 Operation Junction Temperature	T_j			150	$^\circ C$
せん頭逆電圧 Maximum Reverse Voltage	V_{RM}			30	V
出力電流 Average Rectified Forward Current	I_O	50Hz 正弦波, 抵抗負荷 50Hz sine wave, Resistance load	$T_a = 25^\circ C$ プリント基板実装 On glass-epoxy substrate	3.0	A
			$T_c = 83^\circ C$	5.0	
せん頭サージ順電流 Peak Surge Forward Current	I_{FSM}	50Hz 正弦波, 非繰り返し1サイクルせん頭値, $T_j = 25^\circ C$ 50Hz sine wave, Non-repetitive 1 cycle peak value, $T_j = 25^\circ C$		90	A

●電氣的・熱的特性 Electrical Characteristics (指定のない場合 $T_C = 25^\circ C$)

順電圧 Forward Voltage	V_F	$I_F = 1.0A$, パルス測定 Pulse measurement	MAX 0.40	V
		$I_F = 3.0A$, パルス測定 Pulse measurement	MAX 0.46	
逆電流 Reverse Current	I_R	$V_R = V_{RM}$, パルス測定 Pulse measurement	MAX 0.1	mA
接合容量 Junction Capacitance	C_j	$f = 1MHz, V_R = 10V$	TYP 130	pF
熱抵抗 Thermal Resistance	θ_{jc}	接合部・ケース間 Junction to case	MAX 16	$^\circ C/W$
	θ_{jl}	接合部・リード間 Junction to lead	MAX 18	
	θ_{ja}	接合部・周囲間, プリント基板実装 Junction to ambient, On glass-epoxy substrate	MAX 65	

■特性図 CHARACTERISTIC DIAGRAMS



* Sine waveは50Hzで測定しています。
 * 50Hz sine wave is used for measurements.
 * 半導体製品の特性は一般的にバラツキを持っています。
 Typical is a statistical average of the device's ability.
 * Semiconductor products generally have characteristic variation.
 Typical is a statistical average of the device's ability.